

FIG.1

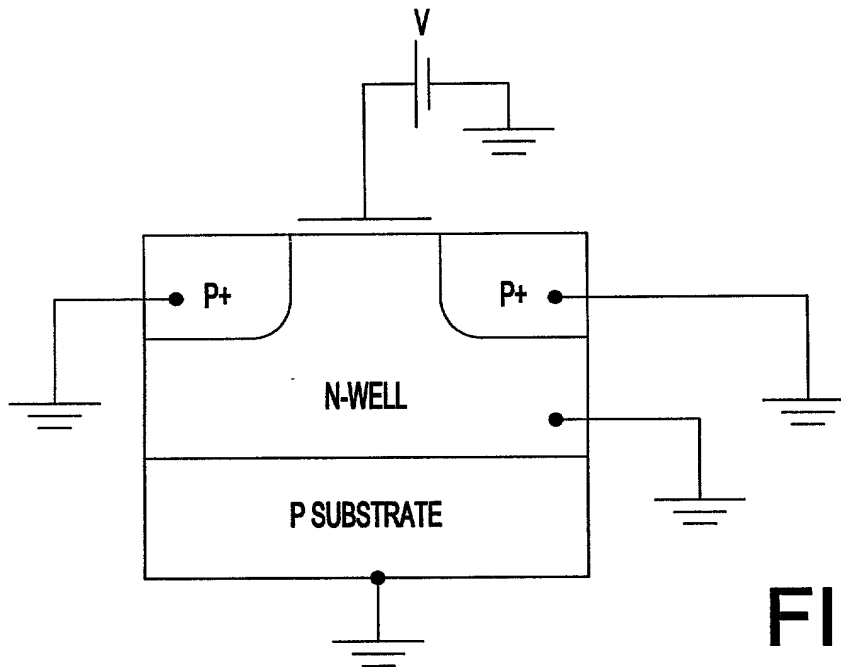


FIG.2

1006395-001001

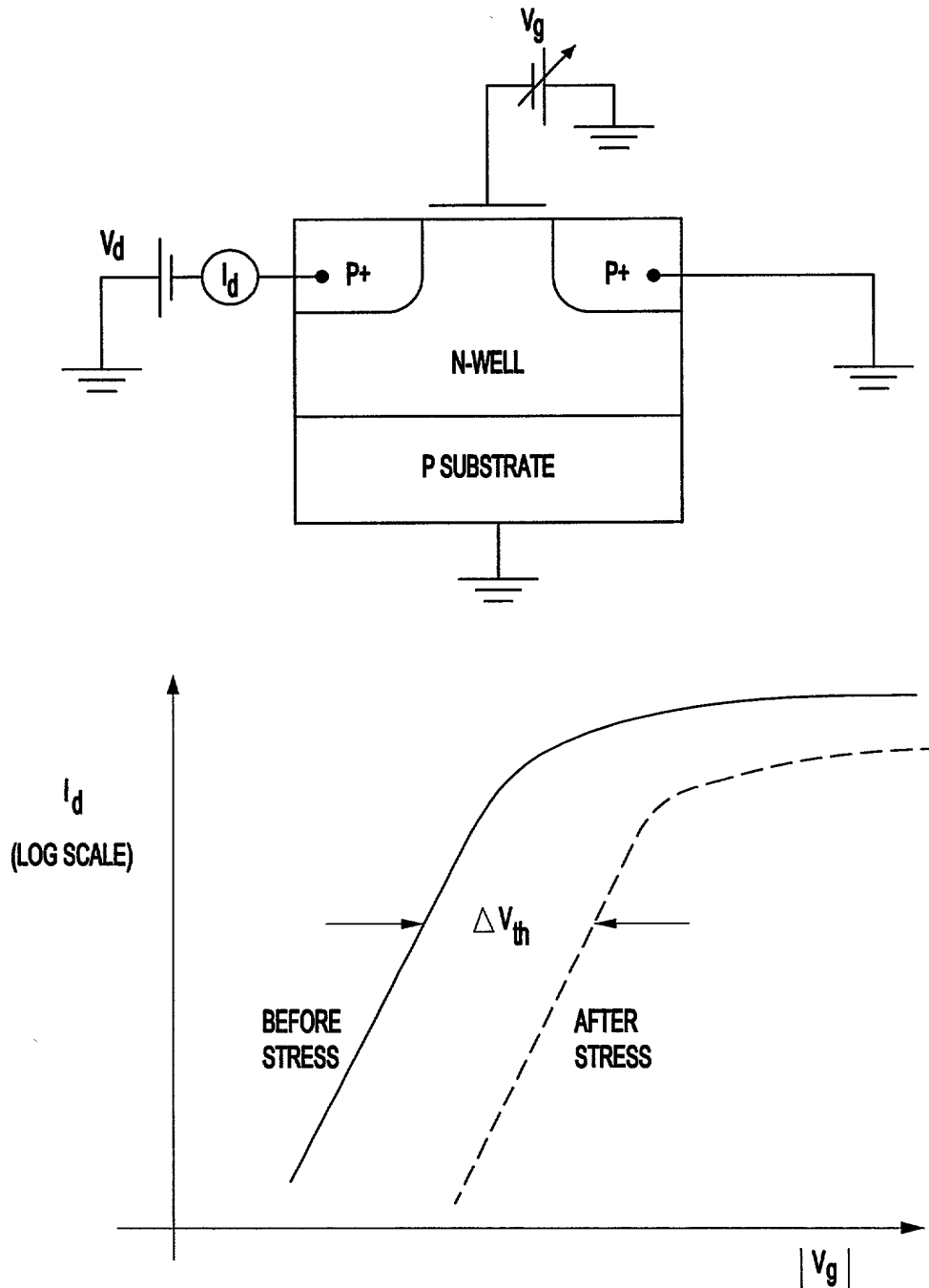
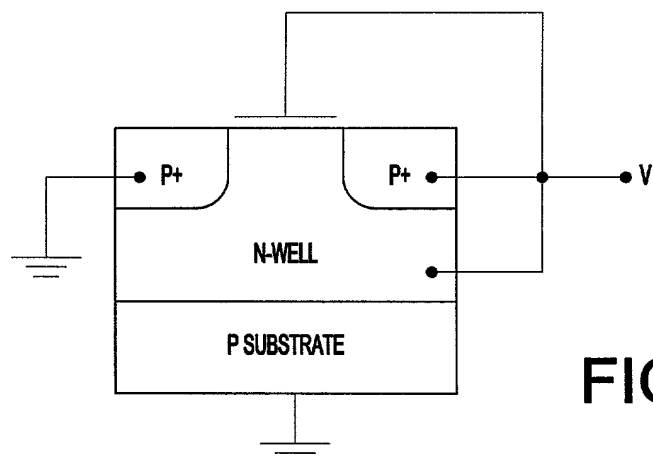
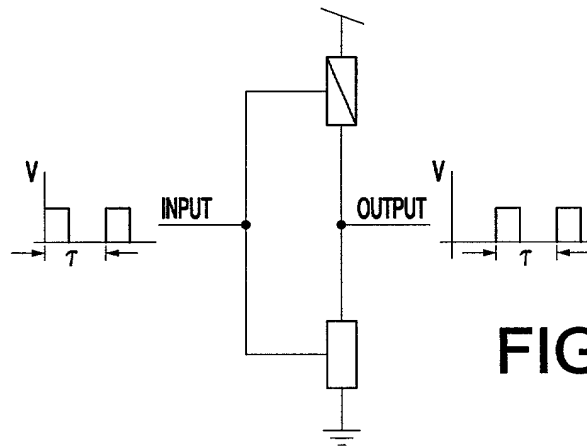
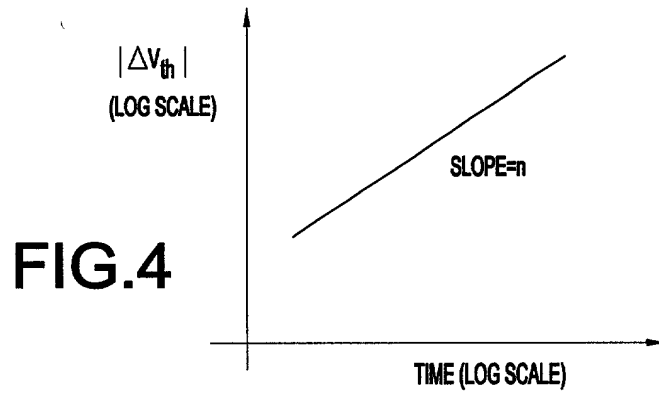


FIG.3



2025-03-06 09:00

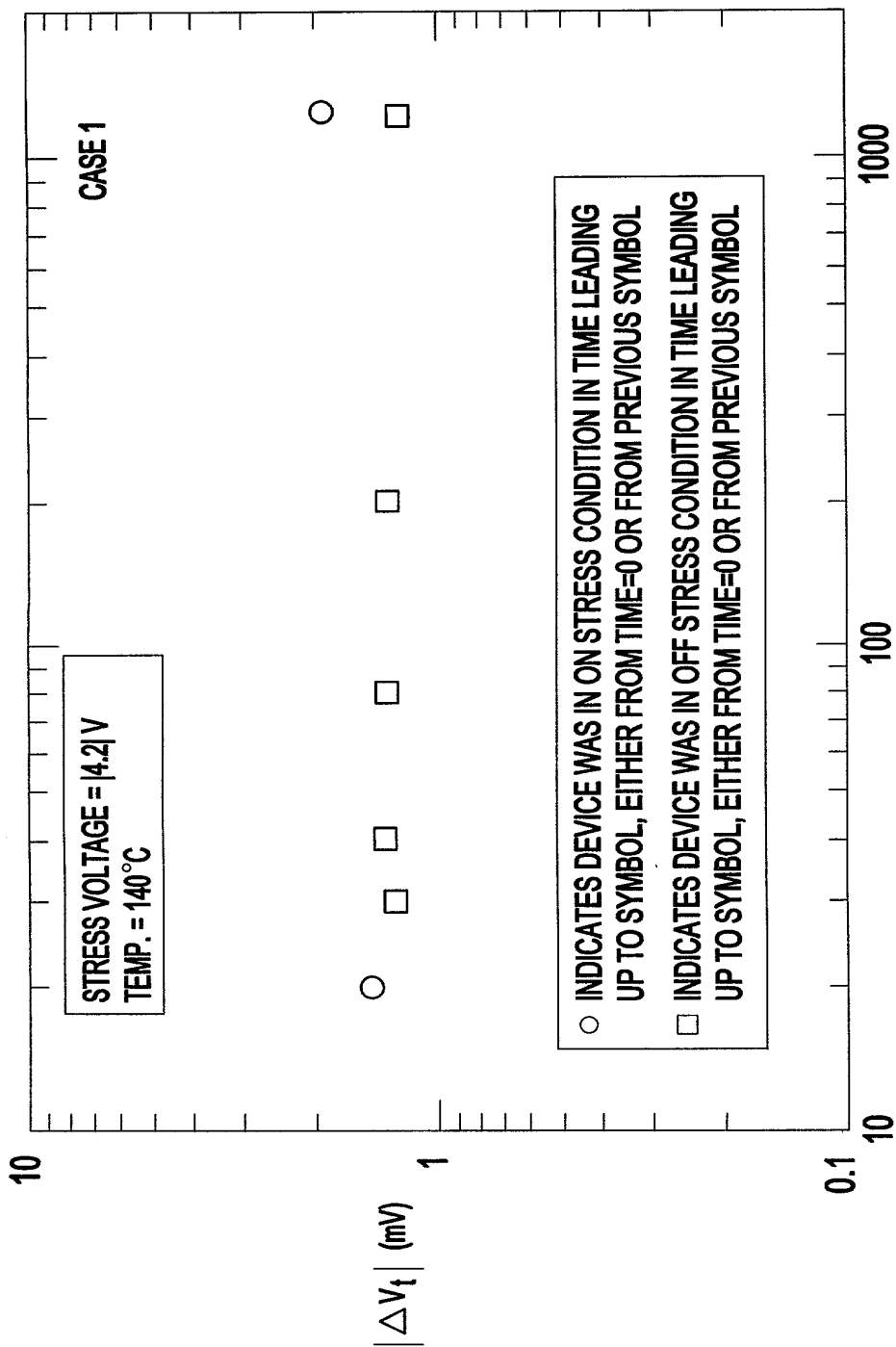


FIG.7A

2021 90° 562E9001

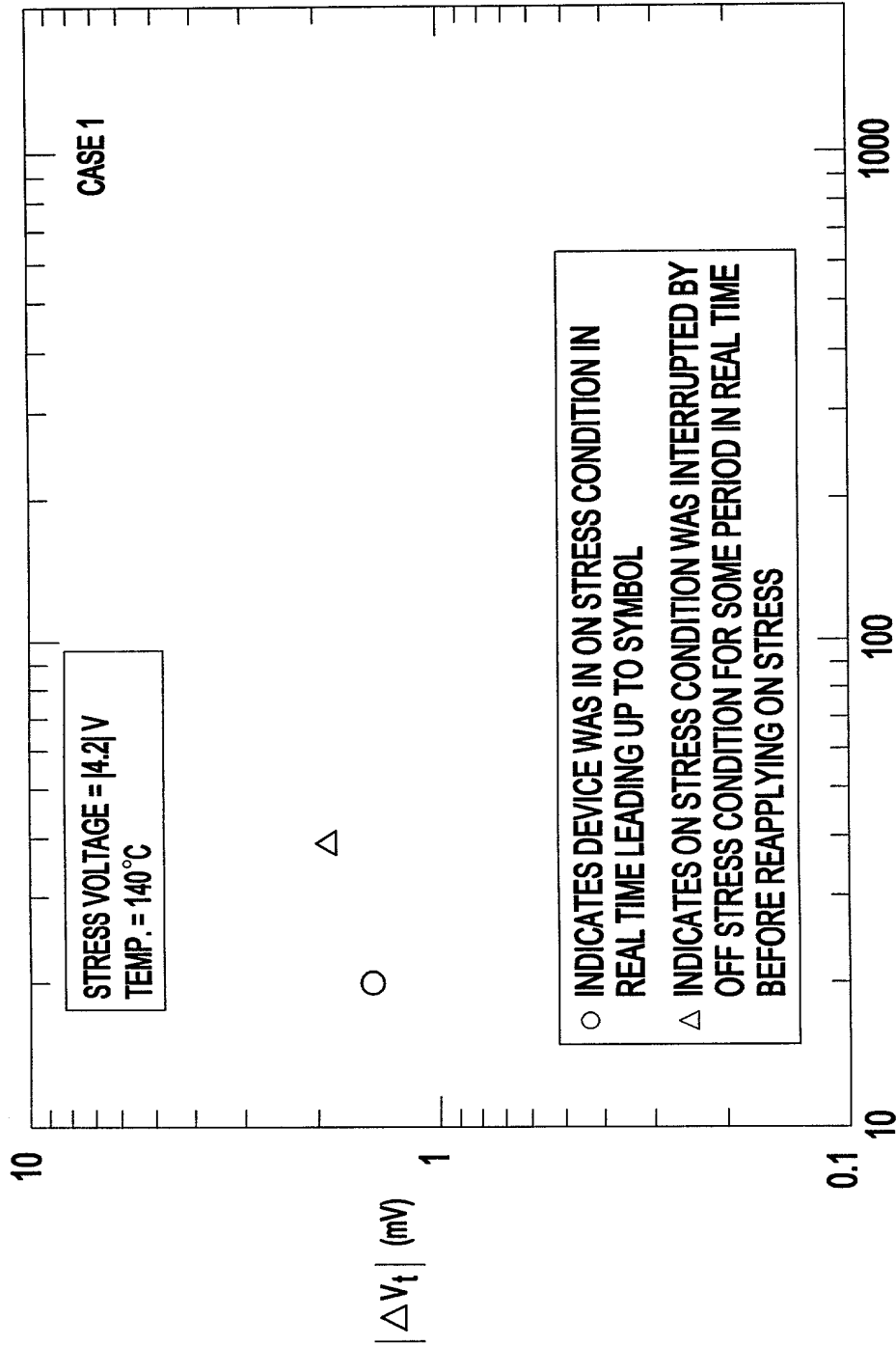


FIG.7B

EFFECTIVE TIME UNDER 'ON' STRESS CONDITION (s)

2024-09-26 14:00:00

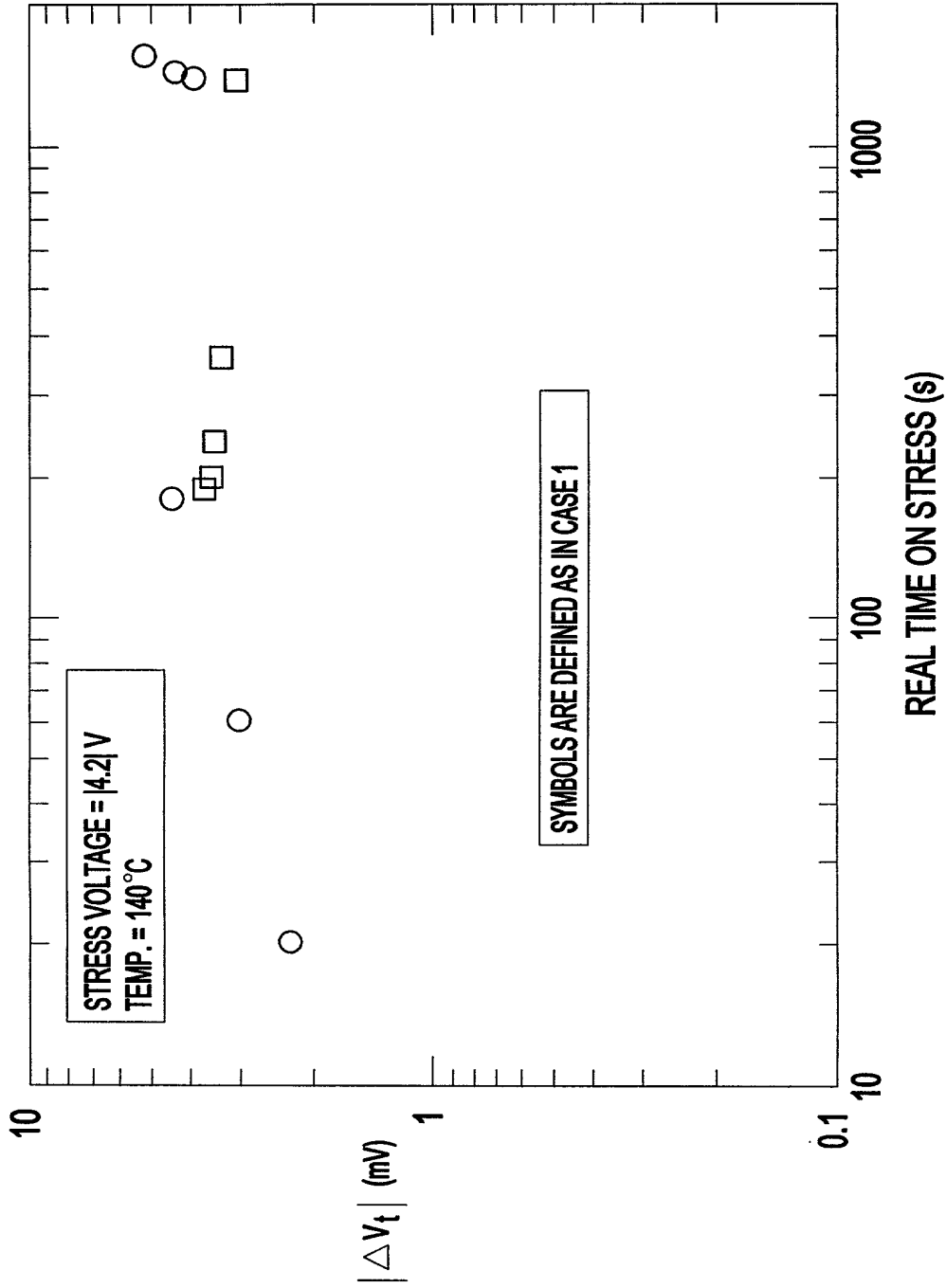


FIG.8A

202790-5625007

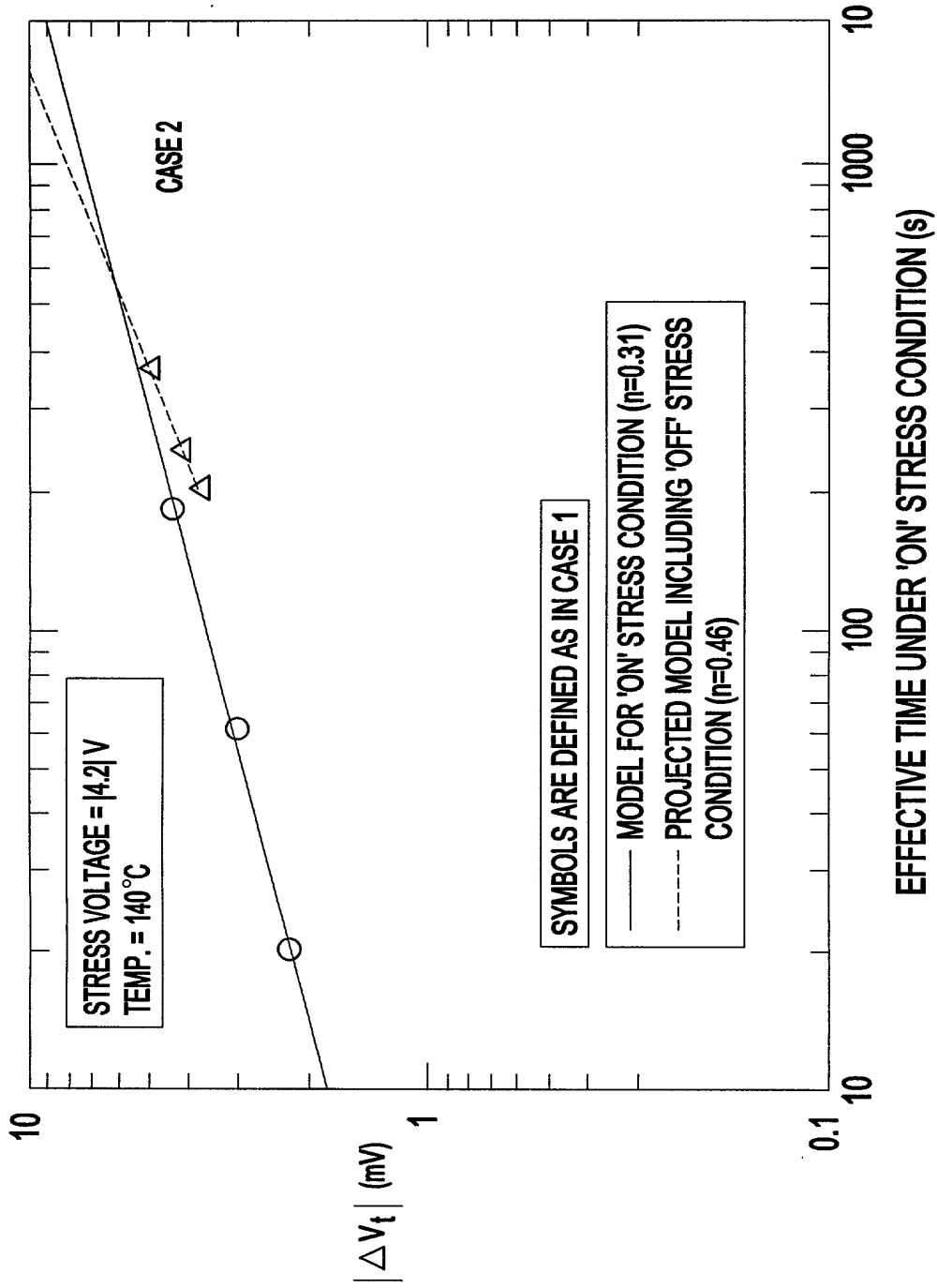


FIG.8B



2021 90° 562E 9001

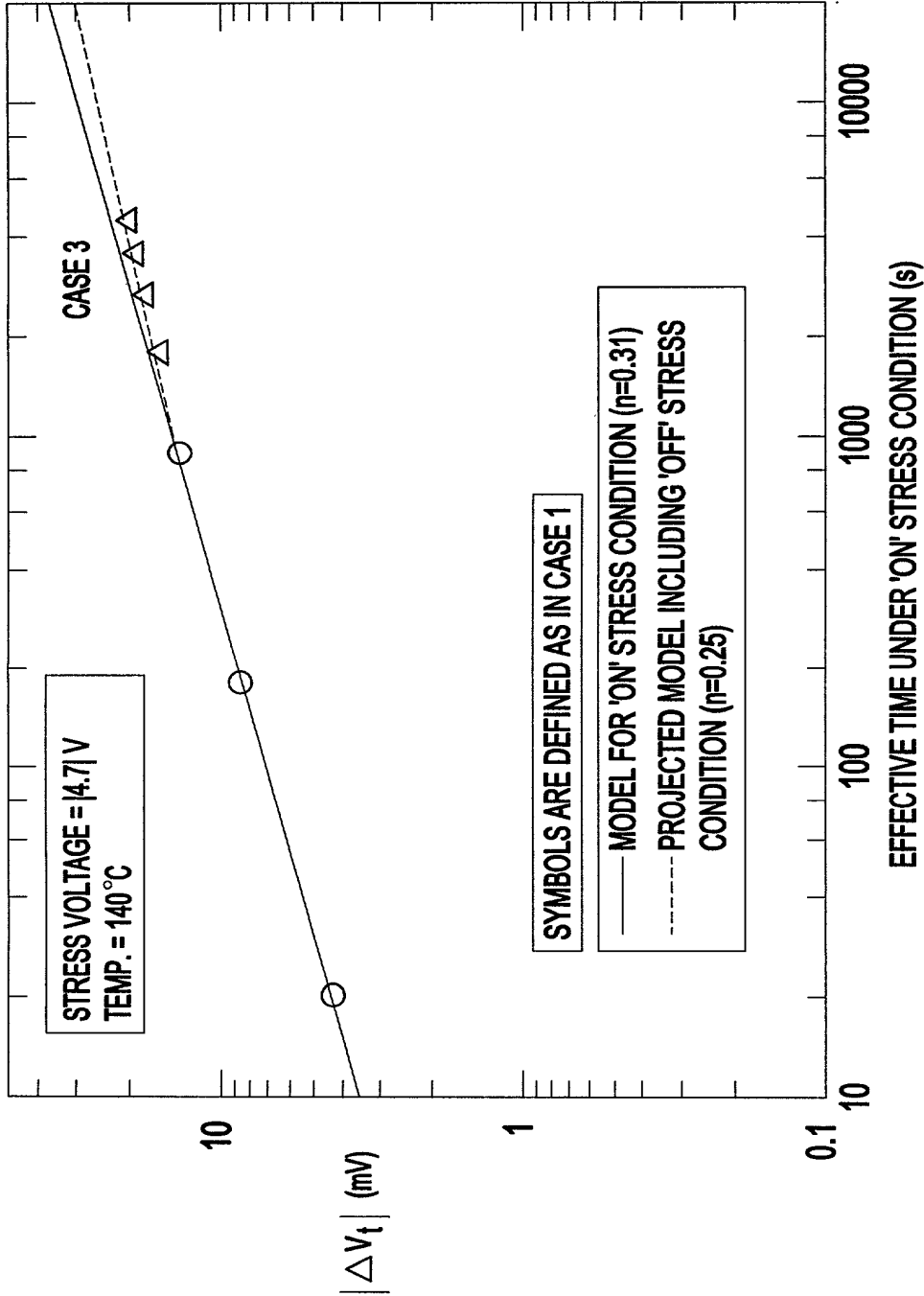


FIG.9B

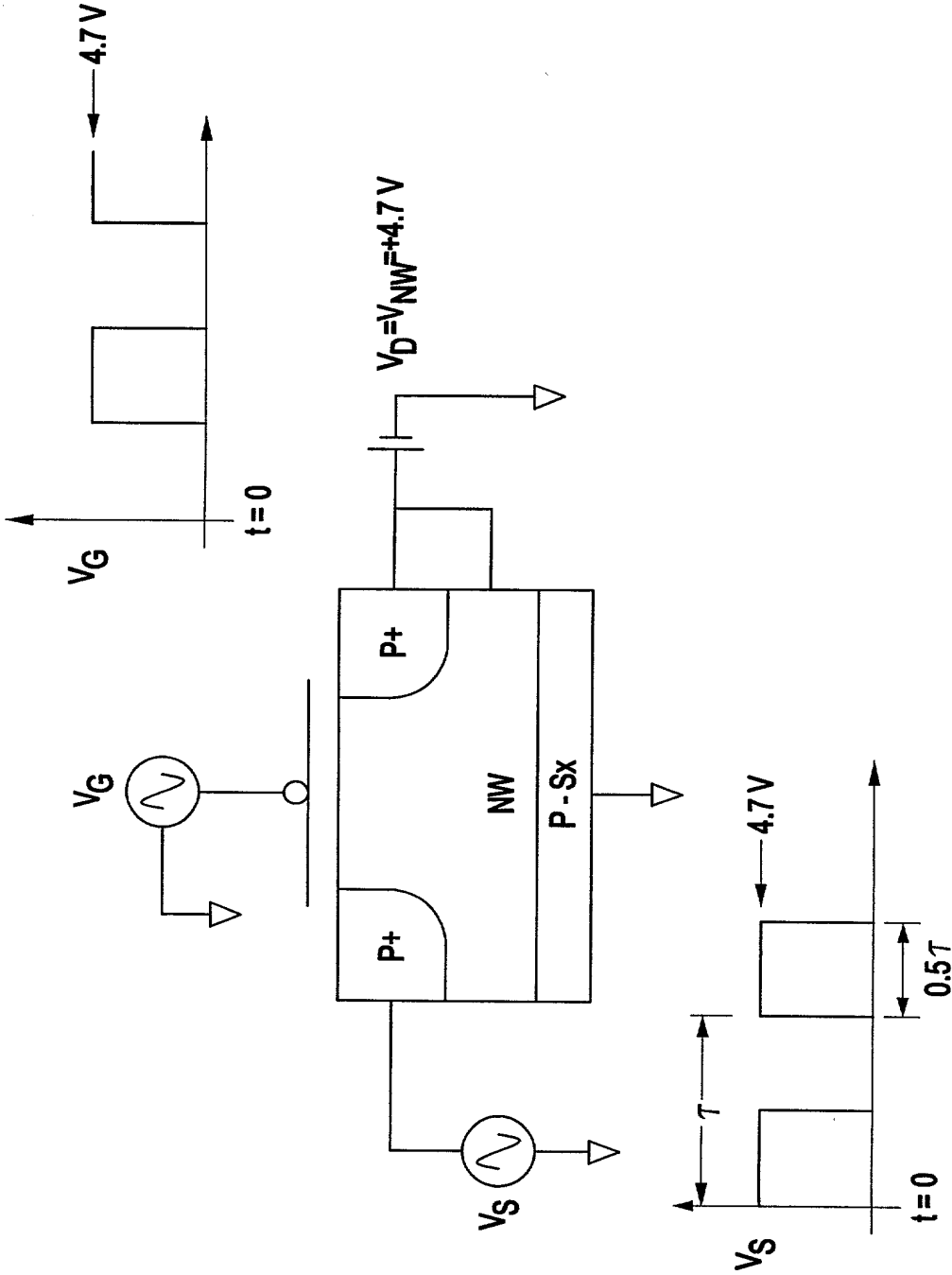


FIG.10

202190-56229001

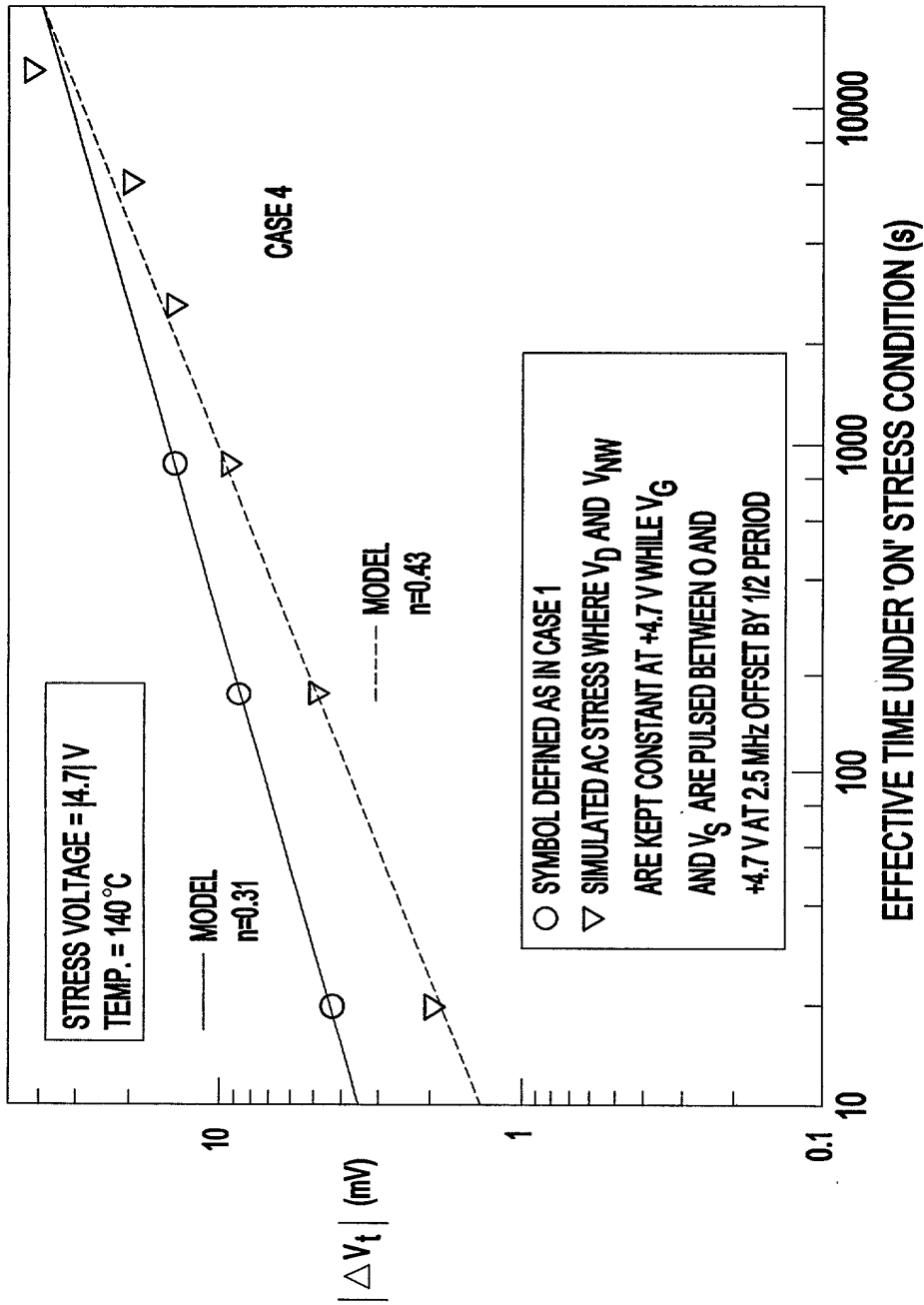
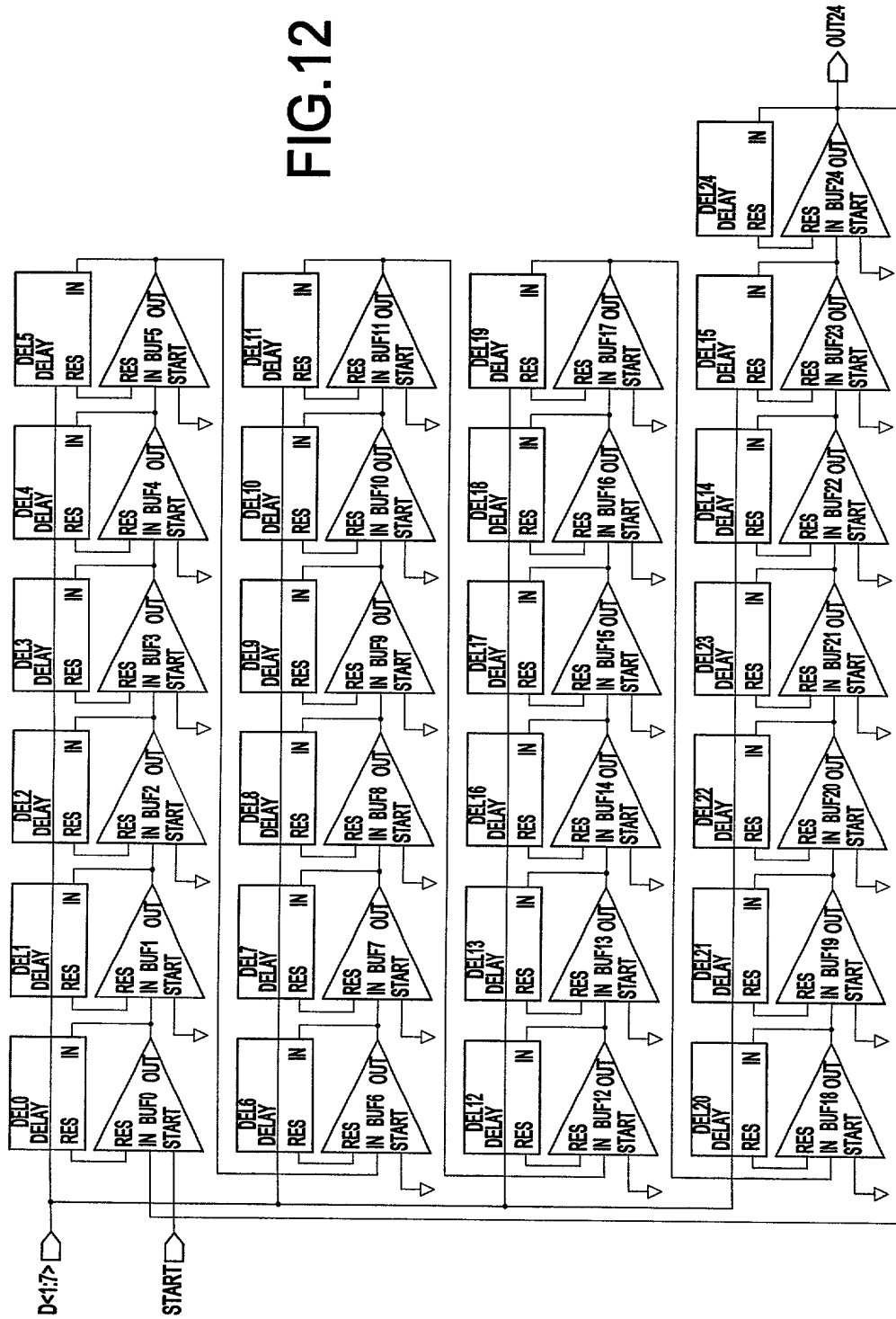


FIG.11

FIG.12



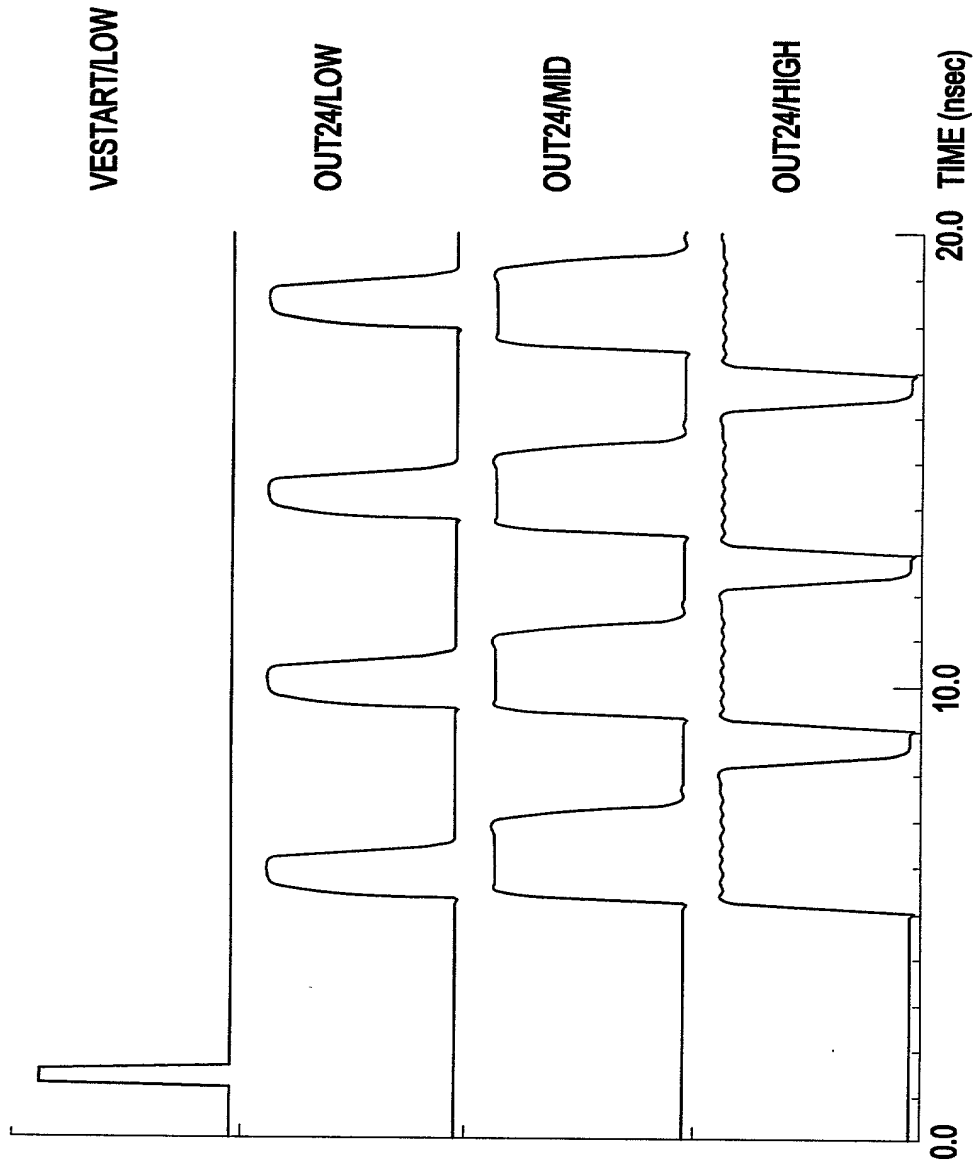


FIG.13

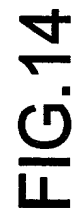


FIG. 14

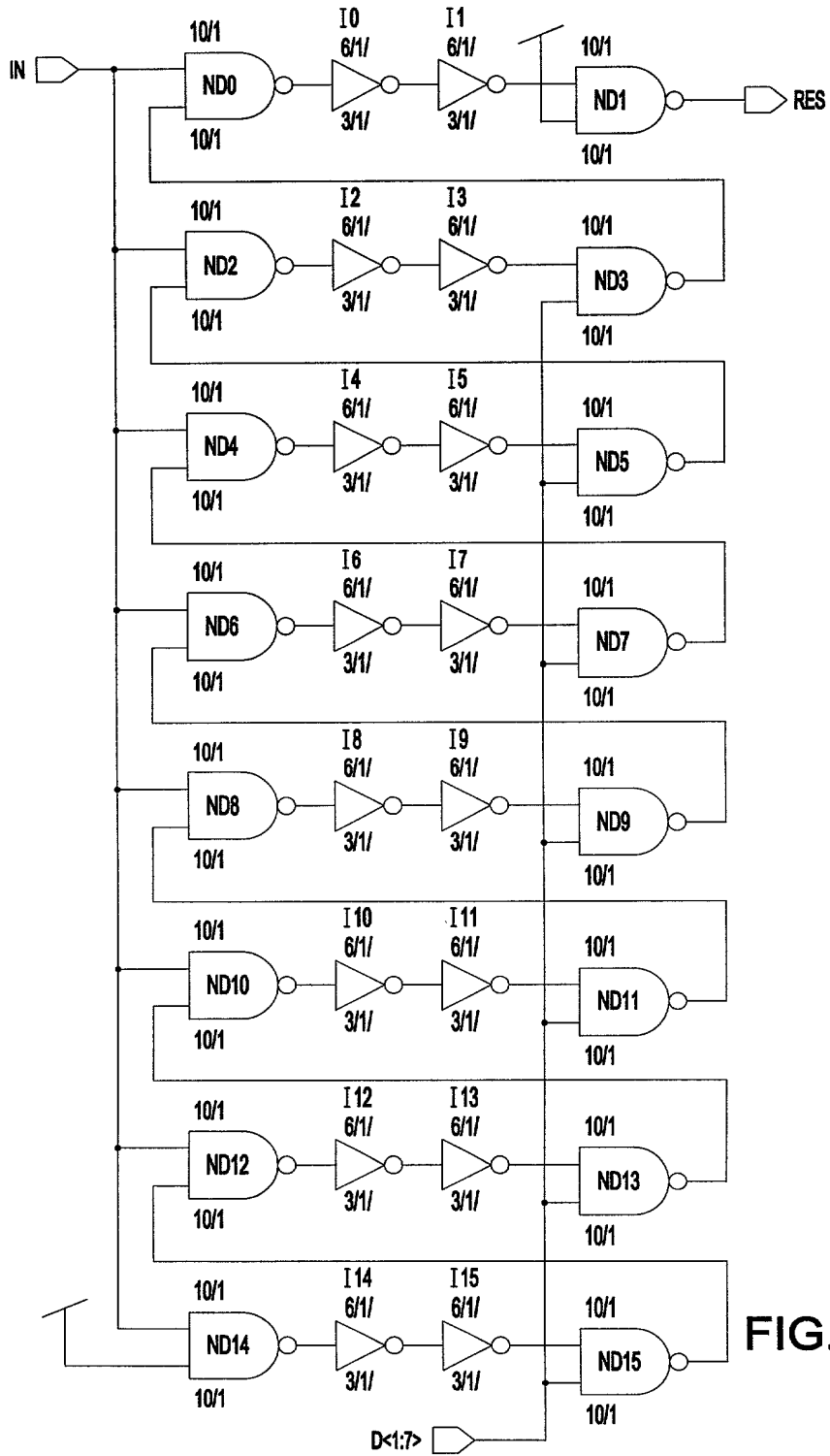


FIG.15

INPUT	FREE RUN	AC STRESS	DC STRESS
SOURCE	VDD	VDD	VDD/GND
GATE	GND	"A.C."	VDD/GND
VPP	VPP	VPP	VPP
bSTRESS1	VDD	VDD	GND
IN	"A.C."	GND	GND
DRAIN	VDD	VDD	VDD/GND
bSTRESS2	VPP	GND	GND

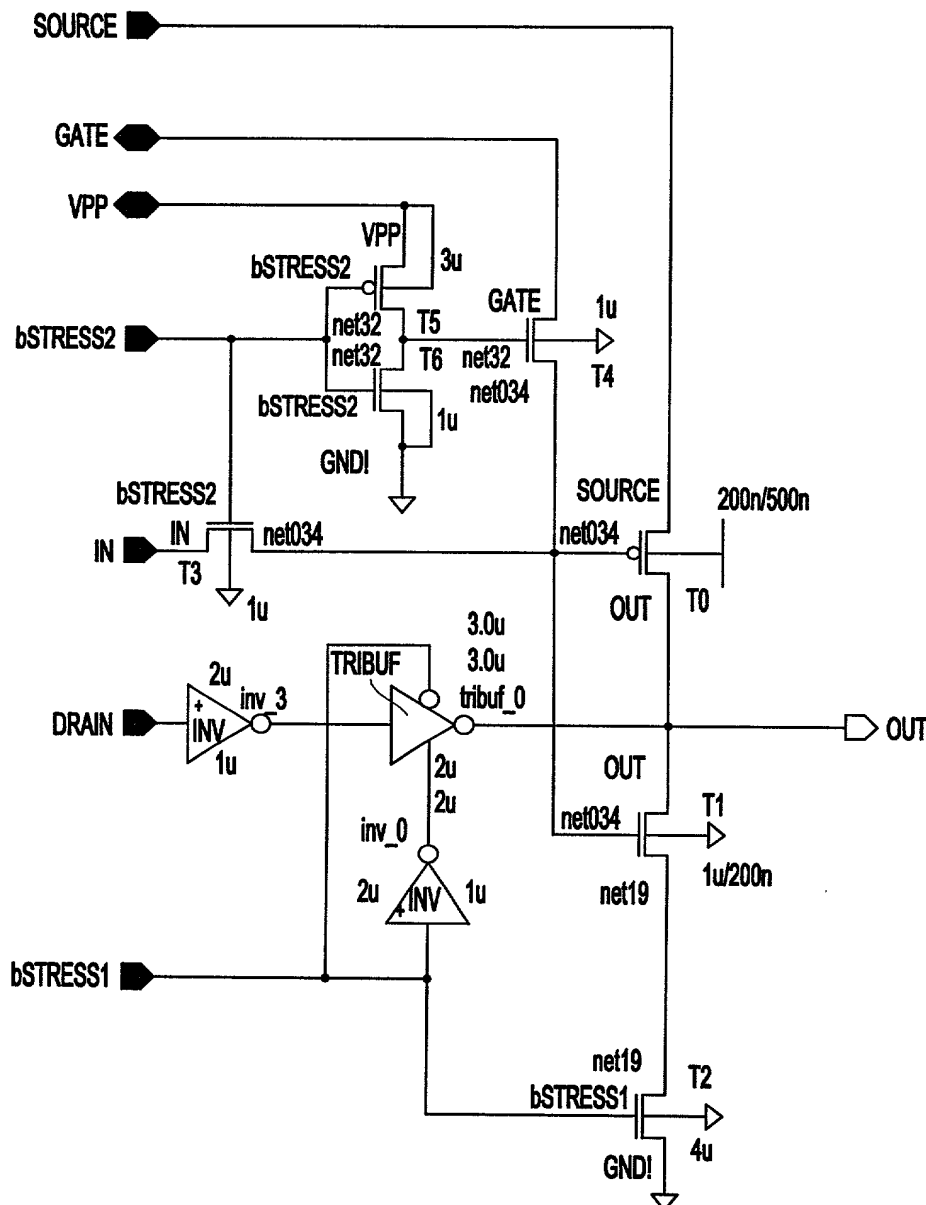


FIG.16

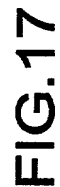




FIG.19

APPLICATION OF PFET DC STRESS IN RING OSCILLATOR
AND DETERMINING DEGRADATION CONSTANTS

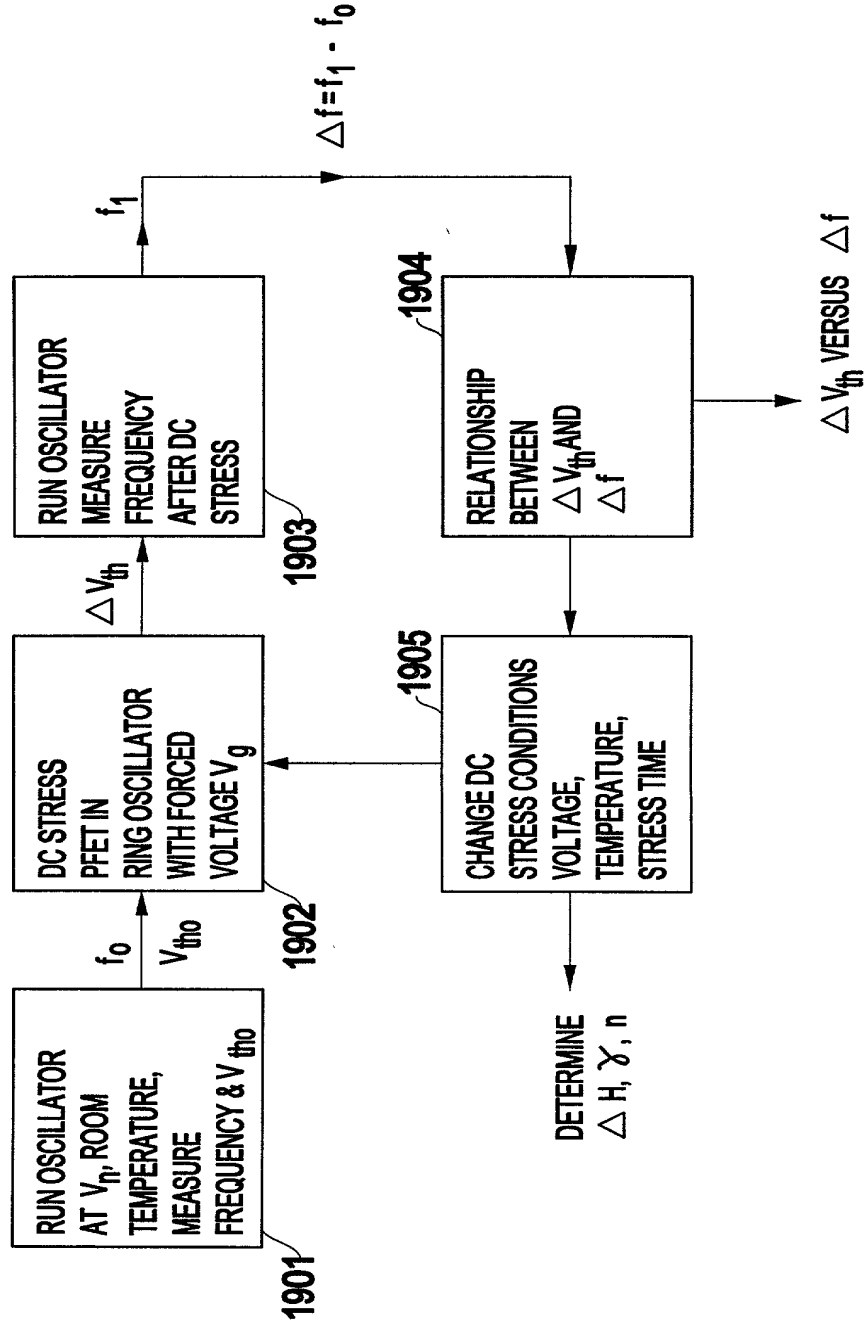


FIG.20

